

(7) ("5231585" | "5537325" | "5751581" | "5886896" | "5972727" |  
 (1036) 235/494.ccls.  
 (72) 235/494.ccls. and updat\$4  
 (19) 235/494.ccls. and ((updat\$4 append\$4) adj5 code\$1)  
 (27) ("4271210" | "4327283" | "4515867" | "4672600" | "4775786"  
 (11307) ion adj1 implant\$1  
 (1458) (ion adj1 implant\$1) same wafer  
 (3) ((ion adj1 implant\$1) same wafer) same contrast  
 (10) ((ion adj1 implant\$1) same wafer) same code\$1  
 (9) (quaternary adj1 code\$3) same shape\$1  
 (0) (quaternary adj1 code\$3) same rectangle\$1  
 (0) (quaternary adj1 code\$3) same oval\$1  
 (1108) oval\$1 same circle\$1 same rectangle\$1  
 (11) (oval\$1 same circle\$1 same rectangle\$1) same code\$1  
 (0) (oval\$1 same circle\$1 same rectangle\$1) and (quaternary ac  
 (122) (quaternary adj1 code\$3)  
 (2) (quaternary adj1 code\$3) same graphic\$4  
 (49) (oval\$1 same circle\$1 same rectangle\$1) and quaternary  
 (1) (oval\$1 same circle\$1 same rectangle\$1) and 235/494.ccls.  
 (1) ((quaternary adj1 code\$3) ) and 235/494.ccls.  
 (3) ("5264386" | "5330924" | "5576573").PN.  
 (0) 5834819.URPN.  
 (4608) multi adj5 code\$1

Process	Queue	Gen
OP	USPAT.USPOPCB.EPC.FG.DERWENT.ISM.TDB	P Busle
Default operator	OK	P Highspeed data transfer ability
(quaternary adj1 code\$3)		

Document ID	Issue Date	Pages	Title	Current OR	Current KR	Retrieval	Inventor	S	C	P	3
US 6156579	20001205	9	Circuit identifier for use with focused ion beam	438/16	257/797		Khatri, Sunil P.				
US 5834819	19981110	13	Semiconductor read-only memory device for permanent storage	257/390	438/401		et al.				
US 20010054155	20011220	38	Privacy and security method and system for a recording and/or replaying teletext signal	713/193	707/9		Wen, Jemmy				
US 20011018	20011018	13	Method and system for a recording and/or replaying teletext signal	713/200	707/9		Hagan, Thomas et al.				
US 20010031130	20010927	37	Optical disk device, optical disk, data recording and/or replaying teletext signal	386/46	386/95		James, Shirley J.				
US 6393047	20020521	21	Quadrature phase spreading codes in code division multiple access	369/112.02	369/120		Nishiwaki, Seiji et al.				
US 6373859	20020416	51	Methods and apparatus for encoding and decoding data	375/140	370/342		Popovic'				
US 6301221	20011009	18	Methods and apparatus for encoding and decoding data	370/479	370/441		Branislav M. Jedwab, Jonathan et al.				
US 6285822	20010904	13	Recording and/or replaying teletext signal	370/208	370/206		Paterson, Kenneth et al.				
US 6030657	20000229	6	Labeling technique for countermeasures product device	386/95	370/210		Graham James, Shirley J.				
US 5991349	19991123	11	Data processing device	427/7	106/31.32		Butland, Charles L. et al.				
				375/355	252/301.16		Chen, Tzang-Kwei				

SPACES [Icons] Browse Queue Clear

DB: USPAT

Default operator: OR

Plucks Synonyms

Highlight all hit terms exactly

(wafer adj25 pits) same pattern

BRS form IS&amp;R form Image Text

	U	Document ID	Issue Date	Pages	Title	Current OR	Current XRef	Retrieval C	Inventor	S	C	P	2	3
1	<input type="checkbox"/>	US 6120749 A	20000919	9	Silicon single crystal with no crystal defect in	423/348	257/610		Takano, Kiyotaka, et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
2	<input type="checkbox"/>	US 5936845 A	19990810	16	IC package and IC probe card with organic substrate	361/767	257/611 257/697		Soejima, Koji, et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
3	<input type="checkbox"/>	US 5738757 A	19980414	24	Planar masking for multi-depth silicon etching	438/603	216/47 216/79		Burns, Brent E., et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
4	<input type="checkbox"/>	US 5733711 A	19980331	8	Process for forming both fixed and variable patterns	430/312	430/22 430/945		Juengling, Werner	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
5	<input type="checkbox"/>	US 5639387 A	19970617	5	Method for etching crystalline bodies	216/39	216/24 216/83		Shahid, Muhammed Afzal	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
6	<input type="checkbox"/>	US 6303993 B1	20011016	7	Method and apparatus for testing bumped die	257/737	257/738 257/778		Wark, James M.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
7	<input type="checkbox"/>	US 6248661 B1	20010619	11	Method for monitoring bubble formation and abnormal via	438/632	438/670		Chien, Wen-Cheng, et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
8	<input type="checkbox"/>	US 6194317 B1	20010227	28	Method of planarizing the upper surface of a	438/692	438/633 438/693		Kaisaki, David A., et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
9	<input type="checkbox"/>	US 6140827 A	20001031	7	Method and apparatus for testing bumped die	324/758	324/158.1		Wark, James M.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
10	<input type="checkbox"/>	US 5946543 A	19990831	19	Semiconductor wafer evaluating method and	438/14	148/DRG.162 438/17		Kimura, Yasuhiro, et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
11	<input type="checkbox"/>	US 5850241 A	19981215	45	Monolithic print head structure and a	347/54	216/2 216/27		Silverbrook, Kia	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>

Find Details

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